Supporting Information

Multi-wavelength tailoring of ZnGa₂O₄ nanosheet phosphor via defect engineering

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Fig. S1 SEM images of (a, b) as-synthesized $ZnGa_2O_4$ nanosheets and annealed

samples at (c) 400 °C, (d) 600 °C, (e) 800 °C and (f) 1000 °C, respectively;



Fig. S2 (a, b) TEM images, (c) HRTEM image and (d) corresponding FFT image of

annealed $ZnGa_2O_4$ nanosheets at 400 °C for 2 h;



Fig. S3 (a, b) TEM images, (c) HRTEM image and (d) corresponding FFT image of

annealed $ZnGa_2O_4$ nanosheets at 600 °C for 2 h;



Fig. S4 (a, b) TEM images, (c) HRTEM image and (d) corresponding FFT image of

annealed $ZnGa_2O_4$ nanosheets at 800 °C for 2 h;



Fig. S5 (a) top-view, (b) side-view and (c) an inclination of 75° view of the schematic diagram of atomic stacking for (111) ZnGa₂O₄ nanosheets; (d) schematic diagram of polyhedral ZnGa₂O₄, [ZnO₄] tetrahedron and [GaO₆] octahedron;



Fig. S6 (a) HRTEM image of (a) as-synthesized and (b) annealed ZnGa₂O₄ nanosheets

at 1000 °C for 2 h; inset is corresponding FFT image;



Fig. S7 Typical SEM images of (a) as-synthesized and (b) annealed hexagonal ZnGa₂O₄

nanosheets at 1000 °C for 2 h;



Fig. S8 EDS spectra of as-synthesized ZnGa₂O₄ nanosheets and annealed samples at

400 °C, 600 °C, 800 °C and 1000 °C for 2 h, respectively;